

AMENDMENTS TO THE ABSTRACT:

Please amend the Abstract as follows:

ABSTRACT OF THE DISCLOSURE

A self-test controller 10 for memory devices 6,8 is provided with an integrated circuit 2. The self-test controller 10 produces physical memory address values ~~Xaddr~~, ~~Yaddr~~ for driving desired memory tests. A mapping circuit 24,26 serves to map these physical memory address signals to logical memory address signals ~~LA[8:0]~~ as required by the particular memory devices 6,8. In this way a generic self-test controller may be provided that is able to drive tests within multiple different memory devices 6,8 by providing a relatively simple mapping circuit 24,26.

{Figure 5}